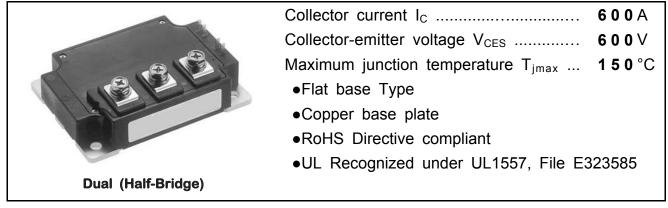


< IGBT MODULES >

CM600DU-12NFH

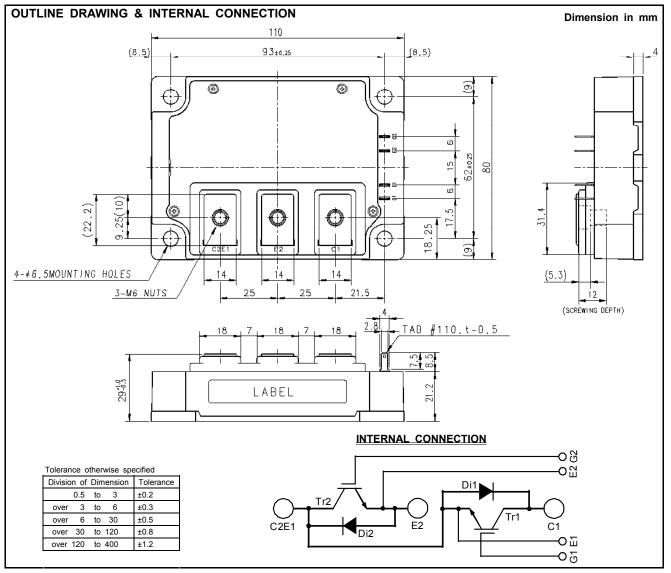
HIGH POWER HIGH FREQUENTLY SWITCHING USE

INSULATED TYPE



APPLICATION

High freqency (30 kHz \sim 60 kHz) switching use: Gradient anplifier, Induction heating, Power supply, etc.



June-2011

MITSUBISHI ELECTRIC CORPORATION

ABSOLUTE	MAXIMUM RATINGS $(I_j=25 \text{ °C})$	uniess otherwise specified)			
Symbol	Item	Conditions	Rating	Unit	
V _{CES}	Collector-emitter voltage	G-E short-circuited	600	V	
V _{GES}	Gate-emitter voltage	C-E short-circuited	±20	V	
1		Operation (Note.5)	600		
I _C	Collector current	Operation, RMS (Note.5)	400	Α	
		Pulse, Repetitive (Note.4)	1200		
P _{tot}	Total newer dissinction	T _C =25 °C ^(Note.2, 5)	1130	w	
P _{tot} '	Total power dissipation	T _c '=25 °C, RMS ^(Note.3, 5)	2350	vv	
(Note.1)	Emitter current	Operation (Note.5)	600		
I _E		Operation, RMS (Note.5)		Α	
IERM (Note.1)		Pulse, Repetitive (Note.4)	1200		
Tj	Junction temperature	-	-40 ~ +150	°C	
T _{stg}	Storage temperature	-	-40 ~ +125		
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V	

ABSOLUTE MAXIMUM RATINGS (T_i=25 °C, unless otherwise specified)

ELECTRICAL CHARACTERISTICS (T_j=25 °C, unless otherwise specified)

Symbol	Item	Conditions Limits Min. Typ. M			Unit		
Symbol	item			Min.	Тур.	Max.	Unit
ICES	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circu	ited	-	-	1	mA
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circu	iited	-	-	0.5	μA
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	I _C =60 mA, V _{CE} =10 V		5	6	7	V
V _{CEsat}	Collector-emitter saturation voltage	I _C =600 A ^(Note.6) ,	T _j =25 °C	-	2.0	2.7	V
CESat	conceter enniter saturation voltage	V _{GE} =15 V	T _j =125 °C	-	1.95	-	v
Cies	Input capacitance			-	-	166	nF
C _{oes}	Output capacitance	V _{CE} =10 V, G-E short-circu	uited	-	-	11	
Cres	Reverse transfer capacitance			-	-	6.0	
Q_{G}	Gate charge	V _{CC} =300 V, I _C =600 A, V _{GE} =15 V		-	3720	-	nC
t _{d(on)}	Turn-on delay time	V_{CC} =300 V, I _C =600 A, V _{GE} =±15 V,		-	-	650	ns
tr	Rise time			-	-	250	
$t_{d(off)}$	Turn-off delay time	R_{G} =2.0 Ω , Inductive load		-	-	800	115
t _f	Fall time			-	-	150	
V _{EC} (Note.1)	Emitter-collector voltage	I _E =600 A ^(Note.6) , G-E short-circuited		-	2.0	2.6	V
t _{rr} ^(Note.1)	Reverse recovery time	V_{CC} =300 V, I _E =600 A, V _{GE} =±15 V,		-	-	200	ns
Q _{rr} (Note.1)	Reverse recovery charge	$R_G=2.0 \Omega$, Inductive load		-	11	-	μC
Eon	Turn-on switching energy per pulse	V_{CC} =300 V, I_{C} = I_{E} =600 A	,	-	11	-	- mJ
E _{off}	Turn-off switching energy per pulse	$V_{GE}=\pm 15$ V, $R_{G}=2.0$ Ω , $T_{j}=125$ °C,		-	27	-	IIIJ
Err (Note.1)	Reverse recovery energy per pulse	Inductive load		-	6.3	-	mJ
r _g	Internal gate resistance	Per switch, T _C =25 °C		-	0.8	-	Ω

THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
		Conditions	Min.	Тур.	Max.	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per IGBT	-	-	0.11	K/W
R _{th(j-c)D}		Junction to case, per FWDi	-	-	0.12	K/W
$R_{th(c-s)}$	Contact thermal resistance (Note.2)	Case to heat sink, per 1/2 module, Thermal grease applied ^(Note.7)	-	20	-	K/kW
R _{th(j-c')Q}	Thermal resistance (Note.3)	Junction to case, per IGBT	-	-	53	K/kW
$R_{th(j-c')D}$		Junction to case, per FWDi	-	-	78	K/kW

MECHANICAL CHARACTERISTICS

Symbol Item	Itom	Conditions		Limits			Unit
	Continuo	115	Min.	Тур.	Max.	Unit	
Mt	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms		Mounting to heat sink	M 6 screw	3.5	4.0	4.5	IN-111
m	Weight	-		-	580	-	g
e _c	Flatness of base plate	On the centerline X, Y	(Note.8)	-100	-	+100	μm

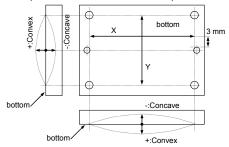
RECOMMENDED OPERATING CONDITIONS (T_a=25 °C)

Symbol Ite	Itom	Conditions		Limits	Unit	
	item	Conditions	Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2	-	300	400	V
V _{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	v
R _G	External gate resistance	Per switch	1.0	-	10	Ω

Note.1: Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).

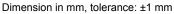
2: Case temperature (T_c) measured point is base plate side. (Refer to the figure of chip location)

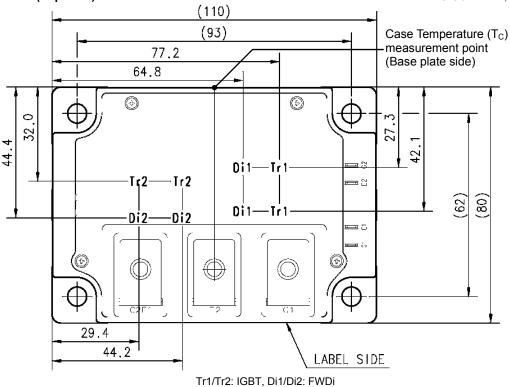
- 3: Case temperature (T_c') and heat sink temperature (T_s') are defined on the each surface of base plate and heat sink just under the chips. (Refer to the figure of chip location)
- 4: Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating.
- 5: Junction temperature (T_j) should not increase beyond T_{jmax} rating.
- 6: Pulse width and repetition rate should be such as to cause negligible temperature rise.
- (Refer to the figure of test circuit) 7: Typical value is measured by using thermally conductive grease of λ =0.9 W/(m K).
- 8: Base plate flatness measurement points are as in the following figure.



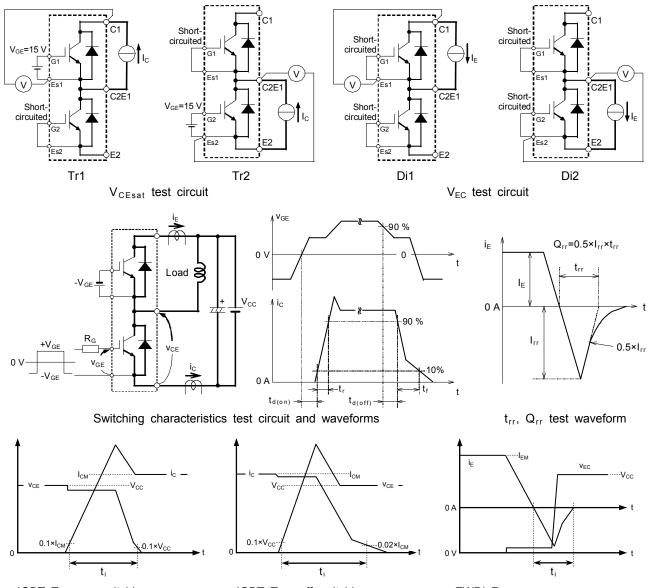
9: No short circuit capability is designed.

CHIP LOCATION (Top view)



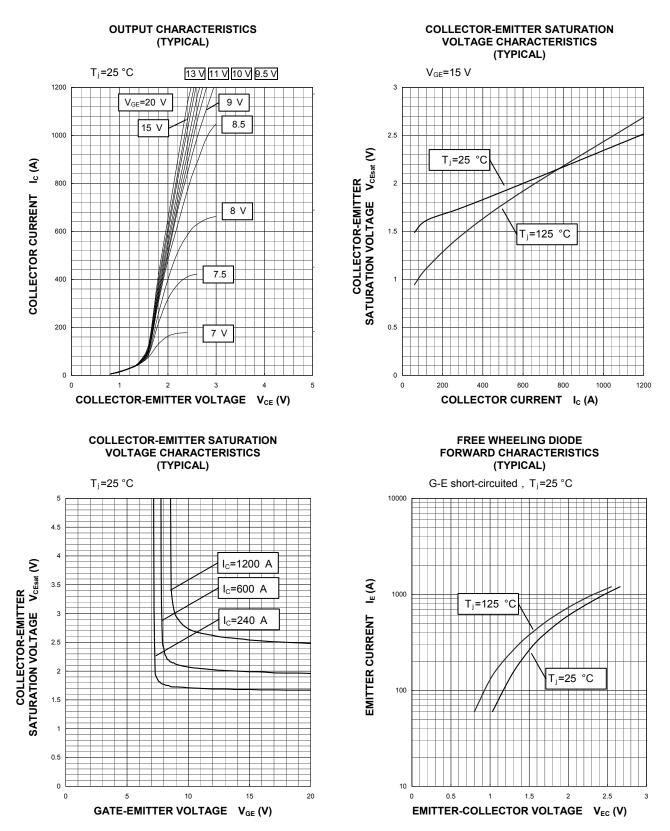


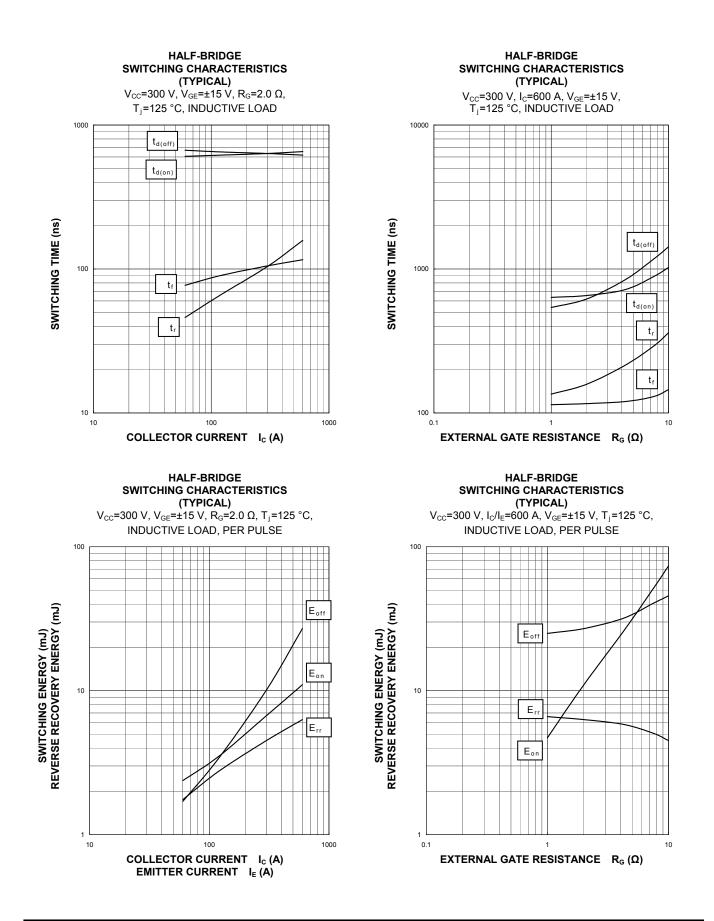
TEST CIRCUIT AND WAVEFORMS

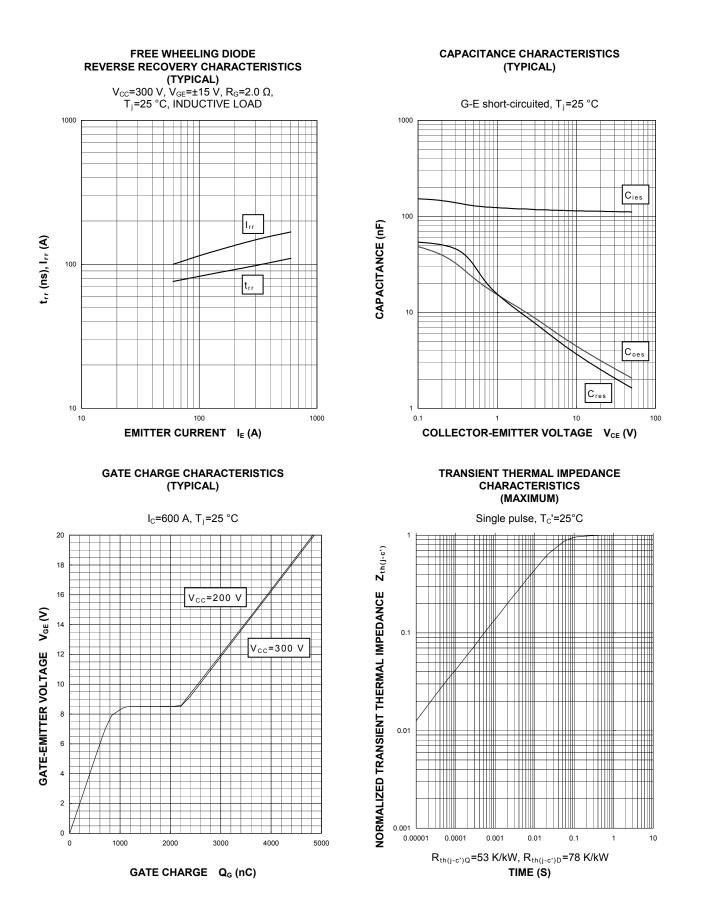


IGBT Turn-on switching energyIGBT Turn-off switching energyFWDi Reverse recovery energyTurn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

PERFORMANCE CURVES







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